



# GaN HEMT 50V, 110W, 4.8-5GHz Power Transistor



## Description

The STAV50110C6 is a dual path 110W, internal matched GaN HEMT, operated from 4.8-5GHz. It features high gain, high efficiency, wide band and low cost, in 10\*6mm open cavity plastic package. It can be configured as a single stage Doherty capable of delivering Pavg of 16W.

There is no guarantee of performance when this part is used outside of stated frequencies.

- Typical Doherty Single-Carrier W-CDMA Characterization Performance:  
VDD = 50 Vdc, IDQA = 55 mA, VGSB = -5.4Vdc, Pout = 42dBm Avg., Input Signal PAR = 10 dB  
@ 0.01% Probability on CCDF (On innogrator application board with device soldered)

| Freq(MHz) | Pout(dBm) | CCDF(dB) | Ppeak(dBm) | Ppeak(W) | ACPR(dBc) | Gain(dB) | Efficiency(%) |
|-----------|-----------|----------|------------|----------|-----------|----------|---------------|
| 4800      | 42.03     | 8.77     | 50.80      | 120.21   | -30.17    | 13.03    | 44.41         |
| 4880      | 41.98     | 8.72     | 50.70      | 117.40   | -30.84    | 13.33    | 46.22         |
| 4960      | 42.00     | 8.73     | 50.73      | 118.22   | -33.26    | 13.23    | 45.44         |

## Applications

- 5G Doherty amplifier within 4.8-5GHz
- C band power amplifier

## Important Note: Proper Biasing Sequence for GaN HEMT Transistors

### Turning the device ON

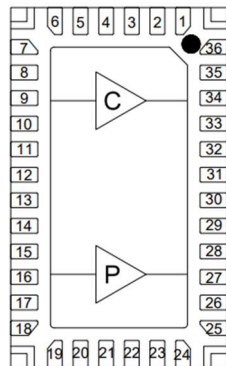
1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

### Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Figure 1: Pin Connection definition

Transparent top view (Backside grounding for source)



| Pin No.     | Symbol      | Description                       |
|-------------|-------------|-----------------------------------|
| 8,9,10,11   | RF IN/Vgs1  | RF Input, Vgs bias for Peak path  |
| 32,33,34,35 | RF OUT/VDD1 | RF Output, VDD bias for Peak path |
| 14,15,16,17 | RF IN/Vgs2  | RF Input, Vgs bias for Main path  |



|   |             |  |
|---|-------------|--|
| 27,28   | RF OUT/VDD2 | RF Output, VDD bias for Main path  |
| 1,24  | DC1,DC2     | DC decoupling for main and peak path   |
| Rest pins   | NC          | No connection  |
| 2,5,7,12,13,18,20,23,25,30,31,36,<br>Package Base | GND         | DC/RF Ground. Must be soldered directly to heatsink or copper coin for CW application. |

**Table 1. Maximum Ratings**

| Rating                         | Symbol    | Value       | Unit |
|--------------------------------|-----------|-------------|------|
| Drain--Source Voltage          | $V_{DSS}$ | +200        | Vdc  |
| Gate--Source Voltage           | $V_{GS}$  | -8 to +0.5  | Vdc  |
| Operating Voltage              | $V_{DD}$  | 55          | Vdc  |
| Maximum gate current           | $I_{gs}$  | 13          | mA   |
| Storage Temperature Range      | $T_{stg}$ | -65 to +150 | °C   |
| Case Operating Temperature     | $T_c$     | +150        | °C   |
| Operating Junction Temperature | $T_j$     | +225        | °C   |

**Table 2. Thermal Characteristics**

| Characteristic  | Symbol          | Value | Unit  |
|---|-----------------|-------|-------|
| Thermal Resistance, Junction to Case by FEA<br>$T_c = 85^\circ\text{C}$ , $P_{diss} = 18\text{W}$ at $P_{avg} = 42\text{dBm}$ WCDMA 1 carrier | $R_{\theta JC}$ | 2.3   | °C /W |

Notes: Based on expected carrier amplifier efficiency of Doherty,  $P_{avg}$  assumes 10% peaking amplifier contribution of total average Doherty rated power. Thermal resistance is measured to package backside

**Table 3. Electrical Characteristics (TA = 25°C unless otherwise noted)**

**DC Characteristics (main path, measured on wafer prior to packaging)**

| Characteristic                 | Conditions  | Symbol       | Min | Typ  | Max | Unit |
|--------------------------------|---|--------------|-----|------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS} = -8\text{V}$ ; $I_{DS} = 5\text{mA}$                                   | $V_{DSS}$    |     | 200  |     | V    |
| Gate Threshold Voltage         | $V_{DS} = 10\text{V}$ , $I_D = 5\text{mA}$                                      | $V_{GS(th)}$ | -4  | -3.2 | -2  | V    |
| Gate Quiescent Voltage         | $V_{DS} = 50\text{V}$ , $I_{DS} = 55\text{mA}$ ,<br>Measured in Functional Test | $V_{GS(Q)}$  |     | -3   |     | V    |

**DC Characteristics (peak path, measured on wafer prior to packaging)**

| Characteristic                 | Conditions  | Symbol       | Min | Typ  | Max | Unit |
|--------------------------------|---|--------------|-----|------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS} = -8\text{V}$ ; $I_{DS} = 8\text{mA}$                                   | $V_{DSS}$    |     | 200  |     | V    |
| Gate Threshold Voltage         | $V_{DS} = 10\text{V}$ , $I_D = 8\text{mA}$                                      | $V_{GS(th)}$ | -4  | -3.1 | -2  | V    |
| Gate Quiescent Voltage         | $V_{DS} = 50\text{V}$ , $I_{DS} = 60\text{mA}$ ,<br>Measured in Functional Test | $V_{GS(Q)}$  |     | -3   |     | V    |

**Ruggedness Characteristics**

| Characteristic           | Conditions   | Symbol | Min | Typ  | Max | Unit |
|--------------------------|--|--------|-----|------|-----|------|
| Load mismatch capability | 5GHz, $P_{out} = 42\text{dBm}$ WCDMA 1<br>Carrier, All phase,<br>No device damages | VSWR   |     | 10:1 |     |      |



Figure 2: Median Lifetime vs. Channel Temperature

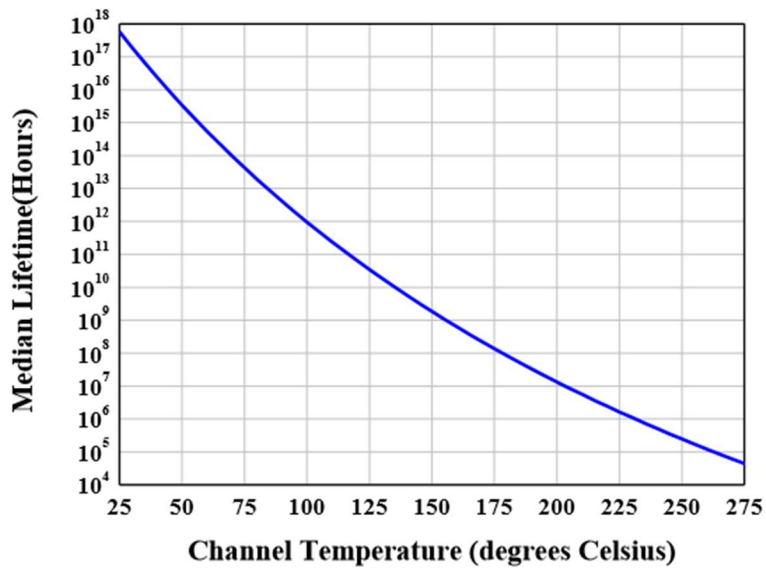


Figure 3: Efficiency and power gain as function of Pout

(VDD = 50 Vdc, Idq = 50 mA, Pulse width=20us, duty cycle=20%)

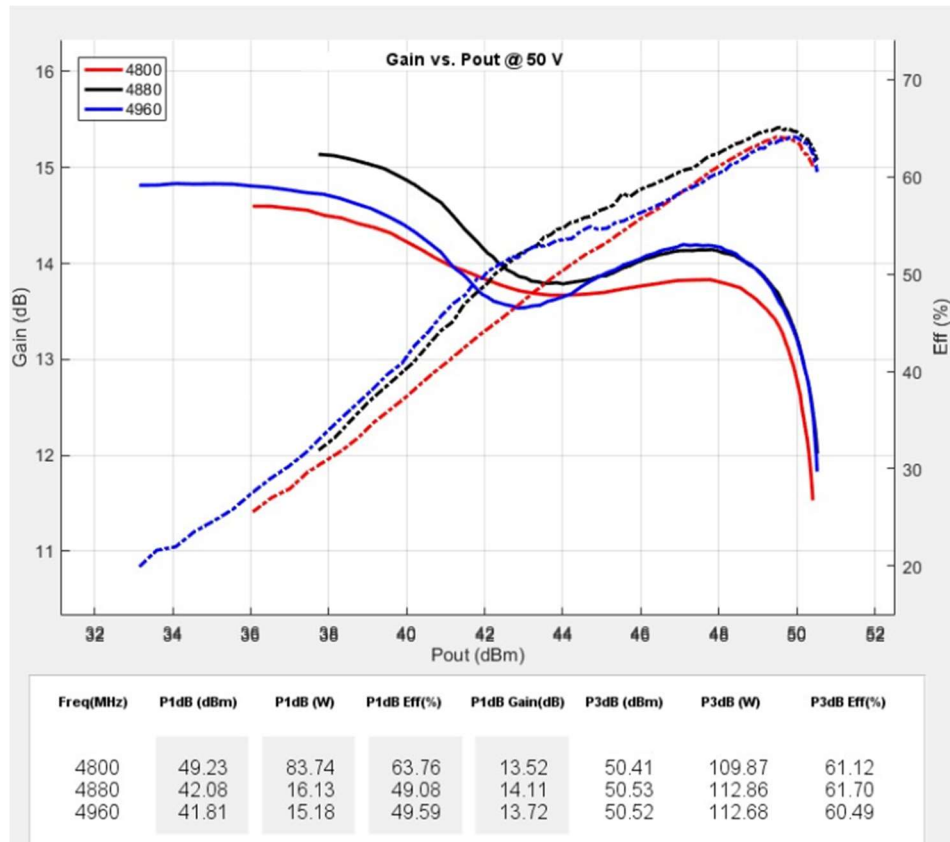




Figure 4: S11/S21 output from Network analyser

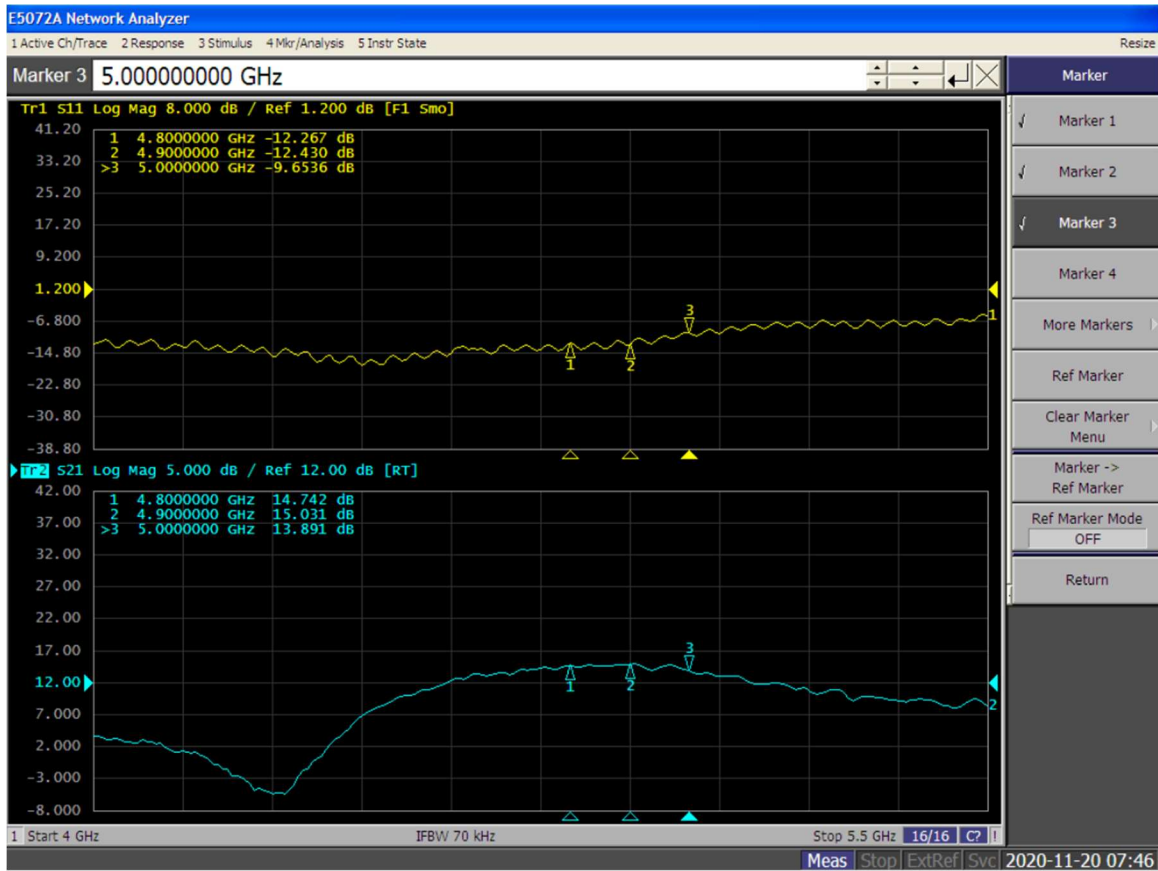
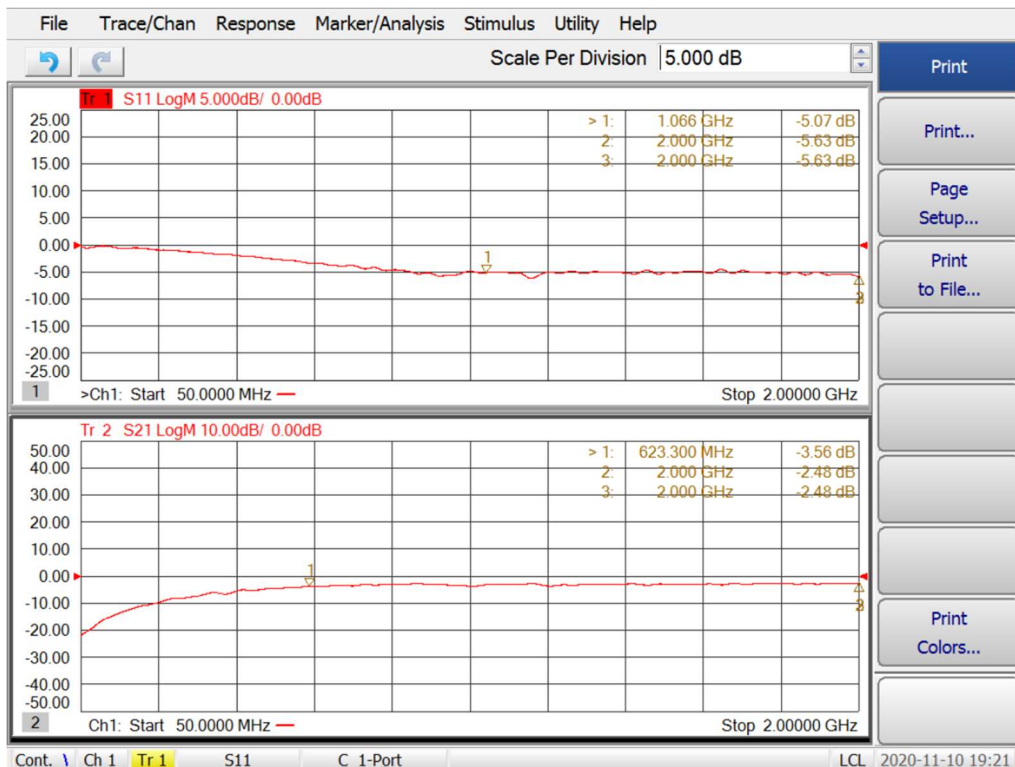


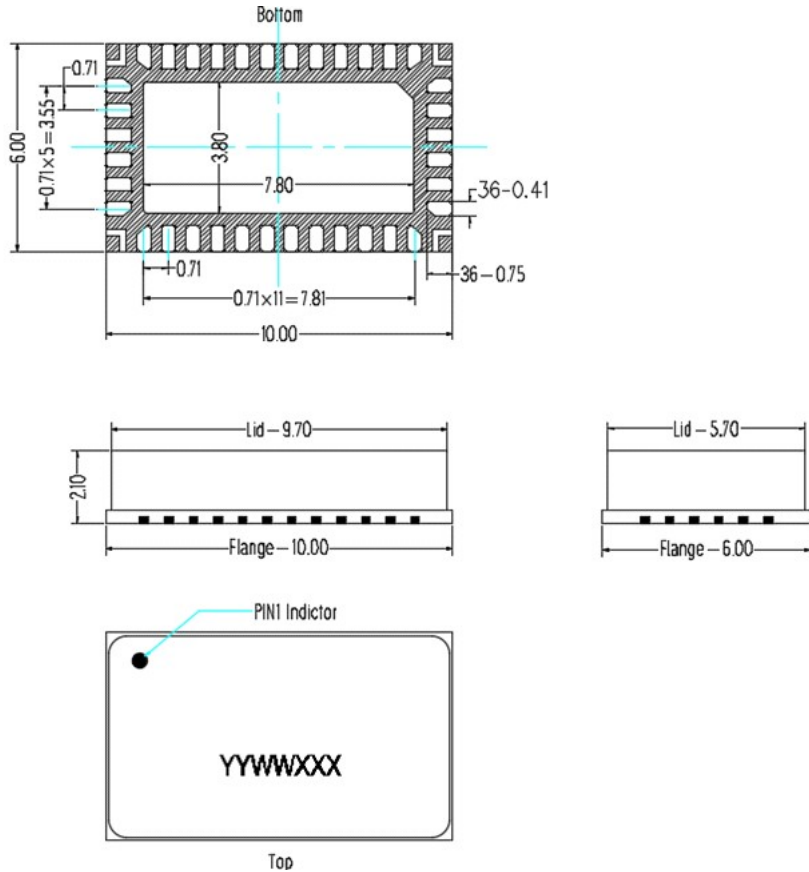
Figure 4: Video impedance test





### Package Dimensions

#### 10\*6 Plastic Package



Notes:

- 1. All dimensions are in mm;
- 2. The tolerances unless specified are ±0.2mm.

### Revision history

Table 4. Document revision history

| Date       | Revision | Datasheet Status               |
|------------|----------|--------------------------------|
| 2020/11/10 | V1.0     | Preliminary Datasheet Creation |
| 2022/12/9  | V1.1     | Update on Pin Definition       |

Application data based on: LWH-20-38

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